

What Is Claimed Is:

1. A method for testing the detectability of at least one flaw in a component, or for evaluating ultrasonic signals of the flaw, comprising the following steps:
 - generating an electronic specification of the flaw, the electronic specification including a two-dimensional or three-dimensional point pattern;
 - manufacturing a test specimen, where for each point of the point pattern, a microcrack in the test specimen is generated at the position of this point;
 - recording and evaluating the ultrasonic signals of the test specimen.
2. The method as recited in Claim 1, wherein the microcracks are produced, using internal laser engraving.
3. The method as recited in Claim 1 or Claim 2, wherein the largest dimension of the microcracks is smaller than the wavelength used for recording the ultrasonic signals.
4. The method as recited in one of Claims 1 through 3, wherein the material, out of which the test specimen is manufactured, is transparent to visible light.
5. The method as recited in Claim 4, wherein crown glass, borosilicate glass, or quartz glass is used as a transparent material.
6. The method as recited in one of Claims 1 through 5, wherein the material, out of which the test specimen is

made, has approximately the same elastic parameters as the material for the component.

7. The method as recited in one of Claims 1 through 6, wherein several specifications having one point pattern each are generated, the point patterns differing with regard to size, shape, and/or orientation, and for each specification,
 - the production of a test specimen being carried out in accordance with this specification, and
 - the recording and evaluation of ultrasonic signals of this test specimen being carried out.
8. Use of the method as recited in one of Claims 1 through 7 for ascertaining or testing the resolution of an ultrasonic testing system, the ultrasonic signals being recorded by a testing system.
9. A device for testing the detectability of at least one flaw in a component, or for evaluating an ultrasonic signal of the flaw, the device comprising the following parts:
 - a device for generating an electronic specification of the flaw, the specification including a two-dimensional or three-dimensional point pattern;
 - a device for producing a test specimen, where for each point of the point pattern, a microcrack is produced at the position of this point;
 - a device for recording and evaluating ultrasonic signals of the test specimen.

10. The device as recited in Claim 9, wherein the device for manufacturing a test specimen is such that the largest dimension of the microcracks is smaller than the wavelength used for recording the ultrasonic signals.
11. The device as recited in Claim 9 or Claim 10, wherein the device for manufacturing a test specimen includes a laser apparatus for producing microcracks with the aid of internal engraving.
12. Use of the device as recited in one of Claims 9 through 11 for ascertaining or testing the resolution of an ultrasonic testing system, the testing system being a part of the device for recording and evaluating the ultrasonic signals.
13. A test specimen for the calibration of an ultrasonic testing system for testing a component or evaluating ultrasonic signals of a flaw, wherein the test specimen includes microcracks, whose positions are predefined by an electronic specification having a two-dimensional or three-dimensional point pattern that corresponds to the flaw.
14. The test specimen as recited in Claim 13, wherein the largest dimension of the microcracks is smaller than the wavelength for the ultrasonic test to be calibrated.
15. The test specimen as recited in Claim 13 or 14, wherein the material, out of which the test specimen is manufactured, is transparent to visible light.

16. The test specimen as recited in Claim 15, wherein the transparent material is crown glass, borosilicate glass, or quartz glass.
17. The test specimen as recited in one of Claims 13 through 16, wherein the material, out of which the test specimen is made, has approximately the same elastic parameters as the material for the component.